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APPLICATION NO. FILING DATE FIRST NAMED INVENTOR ATTORNEY DOCKET NO. CONFIRMATION NO. 09/929,765 08/14/2001 Chih Chin Liao 56370 9374 EXAMINER 21874 7590 03/26/2004 EDWARDS & ANGELL, LLP WARREN, MATTHEW E P.O. BOX 55874 ART UNIT PAPER NUMBER BOSTON, MA 02205 2815

DATE MAILED: 03/26/2004

Please find below and/or attached an Office communication concerning this application or proceeding.

	Application No.	Applicant(s)	
Office Action Summary	09/929,765	LIAO	
	Examiner	Art Unit	
	Matthew E. Warren	2815	
The MAILING DATE of this communication appears on the cover sheet with the correspondence address Period for Reply			
A SHORTENED STATUTORY PERIOD FOR REPLY THE MAILING DATE OF THIS COMMUNICATION. - Extensions of time may be available under the provisions of 37 CFR 1.13 after SIX (6) MONTHS from the mailing date of this communication. - If the period for reply specified above is less than thirty (30) days, a reply If NO period for reply is specified above, the maximum statutory period w Failure to reply within the set or extended period for reply will, by statute, Any reply received by the Office later than three months after the mailing earned patent term adjustment. See 37 CFR 1.704(b). Status 1) Responsive to communication(s) filed on 23 Fe 2a) This action is FINAL. 2b) This	36(a). In no event, however, may a reply be time within the statutory minimum of thirty (30) day will apply and will expire SIX (6) MONTHS from cause the application to become ABANDONE and and this communication, even if timely filed	nely filed s will be considered timely. the mailing date of this communication. D (35 U.S.C. § 133).	
3) Since this application is in condition for allowance except for formal matters, prosecution as to the merits is closed in accordance with the practice under <i>Ex parte Quayle</i> , 1935 C.D. 11, 453 O.G. 213.			
Disposition of Claims			
4) Claim(s) 6,8,11 and 13 is/are pending in the ap 4a) Of the above claim(s) is/are withdray 5) Claim(s) is/are allowed. 6) Claim(s) 6,8,11 and 13 is/are rejected. 7) Claim(s) is/are objected to. 8) Claim(s) are subject to restriction and/o Application Papers 9) The specification is objected to by the Examine 10) The drawing(s) filed on is/are: a) acc Applicant may not request that any objection to the Replacement drawing sheet(s) including the correct 11) The oath or declaration is objected to by the Examine	wn from consideration. r election requirement. er. epted or b) objected to by the drawing(s) be held in abeyance. Se tion is required if the drawing(s) is objected.	e 37 CFR 1.85(a). jected to. See 37 CFR 1.121(d).	
Priority under 35 U.S.C. § 119			
 12) Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f). a) All b) Some * c) None of: 1. Certified copies of the priority documents have been received. 2. Certified copies of the priority documents have been received in Application No. 3. Copies of the certified copies of the priority documents have been received in this National Stage application from the International Bureau (PCT Rule 17.2(a)). * See the attached detailed Office action for a list of the certified copies not received. 			
Attachment(s) 1) Notice of References Cited (PTO-892) 2) Notice of Draftsperson's Patent Drawing Review (PTO-948) 3) Information Disclosure Statement(s) (PTO-1449 or PTO/SB/08) Paper No(s)/Mail Date	4) Interview Summary Paper No(s)/Mail D 5) Notice of Informal I 6) Other:		

DETAILED ACTION

This Office Action is in response to the RCE and Amendment filed on February 23, 2004.

Claim Rejections - 35 USC § 103

The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:

(a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negatived by the manner in which the invention was made.

Claim 6 is rejected under 35 U.S.C. 103(a) as being unpatentable over the Applicant's Prior Art Figures 3 and 4 (APAF) in view of Takahama (JP 6-157238).

In re claim 6, the APAF 3 and 4 shows a BGA package a substrate 10 having a front and back side, a chip 20 mounted on the front side of the substrate, the chip having an array of bond pads 30B, an array of solder balls 40A on the back side of the substrate, and an array of bond fingers 60B beside the chip and electrically connected to the bond pads of that chip. An array of electrically conductive vias (72 & 74) penetrate from the front to the back side of the substrate and connect to the solder balls. The package also comprises a plurality of continuous electrically-conductive traces (70A-70D) for connecting a first subgroup of the bond fingers to corresponding ones of the vias. The continuous traces including at least one trace interposed between a second subgroup of the bond fingers and their corresponding vias. The APAF shows all of the elements of the claims except the electrically conductive bridge. Takahama

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shows (fig. 3 and abstract) shows a semiconductor device having traces (3, 4, and 5) and a conductive bridge (8) in the form of a bond wire spanning in an overhead manner across the traces. The bond wire is free of the interposing traces and has an unfilled gap between the wire and traces. With this configuration, the density of wiring can be increased ultimately increasing the level of integration of the device. Therefore it would have been obvious to one of ordinary skill in the art at the time the invention was made to modify the connections of the APAF by forming conductive bridges spanning over traces as taught by Takahama to increase the wiring density and ultimately improve the integration of the semiconductor device.

In re the limitations concerning the bonding wire being mounted through wire-bonding technology, a "product by process" claim is directed to the product per se, no matter how actually made, In re Hirao, 190 USPQ 15 at 17(footnote 3). See also in re Brown, 173 USPQ 685: In re Luck, 177 USPQ 523; In re Fessmann, 180 USPQ 324: In re Avery, 186 USPQ 116 in re Wertheim, 191 USPQ 90 (209 USPQ 254 does not deal with this issue); and In re Marosi et al, 218 USPQ 289 final product per se which must be determined in a "product by, all of" claim, and not the patentability of the process, and that an old or obvious product, whether claimed in "product by process" claims or not. Note that Applicant has the burden of proof in such cases, as the above case law makes clear. "Even though product-by- process claims are limited by and defined by the process, determination of patentability is based upon the product itself. The patentability of a product does not depend on its method of production. If the product in product-by-process claim is the same as or obvious from a product of the prior art, the

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claim is unpatentable even though the prior product is made by a different process." In re Thorpe, 227 USPQ 964, 966 (Fed. Cir. 1985)(citations omitted).

Claim 8 is rejected under 35 U.S.C. 103(a) as being unpatentable over Applicant's Prior Art Figures 3 and 4 (APAF) in view of Takahama (JP 6-157238) as applied to claim 6 above, and further in view of Abrams (US 3,560,256).

In re claim 8, the APAF and Takahama show all of the elements of the claims except the bond wire made of gold. Abrams discloses a bridge/crossover that is made of gold wires or includes a resistor (col. 4, lines 3-6, & 25-31) and is free of interference with the electrically conductive trace due to the insulating material (27) between the bridge and traces. Therefore it would have been obvious to one of ordinary skill in the art at the time the invention was made to modify the APAF and Takahama by employing gold conductive bridge structures that cross over circuit traces as taught by Abrams to suitably increase the packing density of the circuit.

Claims 11 and 13 are rejected under 35 U.S.C. 103(a) as being unpatentable over the Applicant's Prior Art Figures 3 and 4 (APAF) in view of Takahama (JP 6-157238) and Abrams (US 3,560,256)

In re claims 11 and 13, the APAF 3 and 4 shows a BGA package a substrate 10 having a front and back side, a chip 20 mounted on the front side of the substrate, the chip having an array of bond pads 30B, an array of solder balls 40A on the back side of the substrate, and an array of bond fingers 60B beside the chip and electrically connected to the bond pads of that chip. An array of electrically conductive vias (72 &

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74) penetrate from the front to the back side of the substrate and connect to the solder balls. The package also comprises a plurality of continuous electrically-conductive traces (70A-70D) for connecting a first subgroup of the bond fingers to corresponding ones of the vias. The continuous traces including at least one trace interposed between a second subgroup of the bond fingers and their corresponding vias. The APAF shows all of the elements of the claims except the electrically conductive bridge. Takahama shows (fig. 3 and abstract) shows a semiconductor device having traces (3, 4, and 5) and a conductive bridge (8) in the form of a bond wire spanning in an overhead manner across the traces. The bond wire is free of the interposing traces and has an unfilled gap between the wire and traces. With this configuration, the density of wiring can be increased ultimately increasing the level of integration of the device. Therefore it would have been obvious to one of ordinary skill in the art at the time the invention was made to modify the connections of the APAF by forming conductive bridges spanning over traces as taught by Takahama to increase the wiring density and ultimately improve the integration of the semiconductor device. Neither reference shows that the conductive bridge is a chip resistor. Abrams shows (fig. 1) a circuit in which crossover or conductive bridges are used to increase the packing density of the circuit (col. 2, lines 14-26). The electrically conductive bridge 26 spans in an overhead manner across interposing traces (22c & 22d) and connect one end of a trace 22b to the end of another trace 22a. There is a gap between the bridge and the interposing trace (that gap is filled with an insulating material). The bridge/crossover is made of gold wires or includes a resistor (col. 4, lines 3-6, & 25-31) and is free of interference with the electrically conductive

trace due to the insulating material (27) between the bridge and traces. Therefore it would have been obvious to one of ordinary skill in the art at the time the invention was made to modify the APAF and Takahama by employing conductive bridge structures such as chip resistors that cross over circuit traces as taught by Abrams to also increase the packing density of the circuit.

In re the limitations concerning the resistor being mounted through an SMT technology, see the explanation above for a product by process limitation.

Response to Arguments

Applicant's arguments with respect to claims 6 and 11 have been considered but are most in view of the new ground(s) of rejection.

Conclusion

The prior art made of record and not relied upon is considered pertinent to applicant's disclosure. Farrar (US 6,509,590 B1) as a relevant reference teaches that conductive air bridges have unfilled gaps to further reduce capacitance between the bridge and underlying traces.

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Matthew E. Warren whose telephone number is (571) 272-1737. The examiner can normally be reached on Mon-Thurs, and alternating Fri, 9:00-5:00.

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If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Tom Thomas can be reached on (571) 272-1664. The fax phone number for the organization where this application or proceeding is assigned is 703-872-9306.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

MEW

March 10, 2004

Joms Thomas